

Laboratory	Kailtech Test and Research Centre Private Limited, 141-C, Electronic Complex Industrial Area, Pardesipura, Indore, Madhya Pradesh		
Accreditation Standard	ISO/IEC 17025: 2005		
Discipline	Electronics Testing	Issue Date	18.09.2016
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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
I. SAFETY TESTING FACILITY				
1.	Information Technology Equipment	Power Interface	IS 13252 (Part 1): 2010 (Amd. 1: 2013, Amd. 2: 2015) IEC 60950-1: 2005 (Cl. 1.6)	0.1 A to 15 A 0 to 300 VAC 1 W to 5000 W
		Markings and Instructions	IS 13252 (Part 1): 2010 (Cl. 1.7) (Amd. 1: 2013, Amd. 2: 2015)	Qualitative
		Access to energized part	IS 13252 (Part 1): 2010 (Amd. 1: 2013, Amd. 2: 2015) IEC 60950-1: 2005 (Cl. 2.1.1.1)	Qualitative
		Provisions for earthing and bonding	IS 13252 (Part 1): 2010 (Amd. 1: 2013, Amd. 2: 2015) IEC 60950-1: 2005 (Cl. 2.6.1, 2.6.2, 2.6.3, 2.6.4, 2.6.5)	0.01 VAC to 9.99 VAC 0.01 A to 50 A 0.01 Ω to 1 Ω
		Over current and earth fault protection in Primary circuits	IS 13252 (Part 1): 2010 (Amd. 1: 2013, Amd. 2: 2015) IEC 60950-1: 2005 (Cl. 2.7)	Qualitative
		Electrical Insulation	IS 13252 (Part 1): 2010 (Amd. 1: 2013, Amd. 2: 2015) IEC 60950-1: 2005 (Cl. 2.9)	11 M Ω to 1 T Ω 2 M Ω to 2 G Ω
		Clearance	IS 13252 (Part 1): 2010 (Amd. 1: 2013, Amd. 2: 2015) IEC 60950-1: 2005 (Cl. 2.10.3.1 to 2.10.3.9(a))	0.01 mm to 300 mm,
		Creepage	IS 13252 (Part 1): 2010 (Amd. 1: 2013, Amd. 2: 2015) IEC 60950-1: 2005 (Cl. 2.10.4)	0.01 mm to 300 mm

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	Information Technology Equipment	Stability	IS 13252 (Part 1): 2010 (Amd. 1: 2013, Amd. 2: 2015) IEC 60950-1: 2005 (Cl. 4.1)	Qualitative
		Mechanical Strength	IS 13252 (Part 1): 2010 (Amd. 1: 2013, Amd. 2: 2015) IEC 60950-1: 2005 (Cl. 4.2.1 to 4.2.7)	Qualitative
		Thermal Requirements	IS 13252 (Part 1): 2010 (Amd. 1: 2013, Amd. 2: 2015) IEC 60950-1: 2005 (Cl. 4.5)	Ambient to 400 °C
		Resistance to fire	IS 13252 (Part 1): 2010 (Amd. 1: 2013, Amd. 2: 2015) IEC 60950-1: 2005 (Cl. 4.7)	Qualitative
		Touch Current & Protective conductor Current	IS 13252 (Part 1): 2010 (Amd. 1: 2013, Amd. 2: 2015) IEC 60950-1: 2005 (Cl. 5.1)	0 to 4 mA
		Electric Strength	IS 13252 (Part 1): 2010 (Amd. 1: 2013, Amd. 2: 2015) IEC 60950-1: 2005 (Cl. 5.2)	Qualitative 0.01 kV to 10 kV , LC. 0.01 kV
2.	Self Ballasted Led Lamps For General Lighting Services	Marking	IS 16102 (Part 1): 2012 (Cl. 5)	Qualitative
		Interchangeability	IS 16102 (Part 1): 2012 (Cl. 6)	Qualitative (Torque. Upto 10 Nm)
		Protection Against Accidental Contact with Live Parts	IS 16102 (Part 1): 2012 (Cl. 7)	Qualitative (Force Upto 500 N)

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Self Ballasted Led Lamps For General Lighting Services	Insulation Resistance And Electric Strength After Humidity Treatment	IS 16102 (Part 1): 2012 (Cl. 8)	Qualitative (Temp 10 °C to 50 °C, Upto 95 % RH, 11 MΩ to 1 TΩ, 2 MΩ to 2 GΩ, 0.01 kV to 10 kV)
		Mechanical Strength	IS 16102 (Part 1): 2012 (Cl. 9)	Qualitative (Torque Upto 10 Nm)
		Cap Temperature Rise	IS 16102 (Part 1): 2012 (Cl. 10)	Upto 300 °C
		Resistance to heat	IS 16102 (Part 1): 2012 (Cl. 11)	Qualitative
		Resistance to flame and ignition	IS 16102 (Part 1): 2012 (Cl. 12)	Qualitative
		Fault Condition	IS 16102 (Part 1): 2012 (Cl. 13)	Qualitative
		Creepage distances and clearances	IS 16102 (Part 1): 2012 (Cl. 14)	0.01 mm to 300 mm
3.	Lamp Control gear	Marking	IS 15885 (Part 1): 2011 (Cl. 7) Amd. 1: 2015 IS 15885 (Part 2/Sec XIII): 2012 (Cl. 7) IS 15885 (Part 2/Sec III): 2011 (Cl. 7)	Qualitative (Durability Test)
		Protection Against Accidental Contact with Live Parts	IS 15885 (Part 1): 2011 (Cl. 10) Amd. 1: 2015 IS 15885 (Part 2/Sec XIII): 2012 (Cl. 8) IS 15885 (Part 2/Sec III): 2011 (Cl. 8)	Qualitative (Force Upto 500 N)

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	Lamp Control gear	Provision for Protective Earthing	IS 15885 (Part 1): 2011 (Cl. 9) Amd. 1: 2015 IS 15885 (Part 2/Sec XIII): 2012 (Cl. 10) IS 15885 (Part 2/Sec III): 2011 (Cl. 10)	0.01 VAC to 9.99 VAC 0.01 A to 50 A Upto 300 mm 0.01 Ω to 1 Ω
		Moisture Resistance And Insulation	IS 15885 (Part 1): 2011 (Cl. 11) Amd. 1: 2015 IS 15885 (Part 2/Sec XIII): 2012 (Cl. 11) IS 15885 (Part 2/Sec III): 2011 (Cl. 11)	Qualitative (10 °C to 50 °C, Upto 95 % RH, 11 M Ω to 1 T Ω , 2 M Ω to 2 G Ω)
		Electric Strength	IS 15885 (Part 1): 2011 (Cl. 12) Amd. 1: 2015 IS 15885 (Part 2/Sec XIII): 2012 (Cl. 12) IS 15885 (Part 2/Sec III): 2011 (Cl. 12)	Qualitative (0.01 kV to 10 kV)
		Creepage distances and clearances	IS 15885 (Part 1): 2011 (Cl. 16) Amd. 1: 2015 IS 15885 (Part 2/Sec XIII): 2012 (Cl. 17) IS 15885 (Part 2/Sec III): 2011 (Cl. 18)	0.01 mm to 300 mm
		Resistance to Heat, Fire and Tracking	IS 15885 (Part 1): 2011 (Cl. 18) Amd. 1: 2015 IS 15885 (Part 2/Sec XIII): 2012 (Cl. 19) IS 15885 (Part 2/Sec III): 2011 (Cl. 20)	Qualitative

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4.	Audio Video And Similar Electronic Apparatus	Markings and Instructions	IS 616: 2010 IEC 60065: 2014 (Cl. 5)	Qualitative
		Heating Under Normal Operating Conditions	IS 616: 2010 IEC 60065: 2014 (Cl. 7.1)	Ambient to 400 °C
		Electric Shock Hazard Under Normal Operating Conditions	IS 616: 2010 IEC 60065: 2014 (Cl. 9)	Qualitative (Upto 1000 VAC, Upto 1000 VDC, Upto 500 N)
		Insulation requirements	IS 616: 2010 IEC 60065: 2014 (Cl. 10)	11 MΩ to 1 TΩ 2 MΩ to 2 GΩ 0 to 10 kVAC 10 °C to 50 °C Upto 95 % RH
		Mechanical Strength	IS 616: 2010 IEC 60065: 2014 (Cl. 12)	Qualitative (Force up to 500N)
		Clearance	IS 616: 2010 IEC 60065: 2014 (Cl. 13.3.1 to 13.3.4(a))	0 to 300 mm
		Creepage	IS 616: 2010 IEC 60065: 2014 (Cl. 13.4)	0 to 300 mm
		Provision for Protective Earthing	IS 616: 2010 / IEC 60065: 2014 (Cl. 15.2)	0.01 VAC to 9.99 VAC 0.01 A to 50A 0.01 Ω to 1 Ω
		Device Formatting a Part of the Mains Plug	IS 616: 2010 IEC 60065: 2014 (Cl. 15.4)	Qualitative (Torque Upto 10 Nm Hot Air Oven up 300 °C)
		Stability & Mechanical Hazard	IS 616: 2010 IEC 60065: 2014 (Cl. 19.1 to 19.4)	Qualitative (Force Upto 500 N)

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II. ENVIRONMENTAL TEST FACILITY				
1.	Electronic items/ Electrical Items/ Automotive items/ Equipments/ Microcircuits/	Cold test	IS 9000 (Part 2/Sec I to 4): 1977 (RA 2007)	Qualitative (6 Feet x 4 Feet x 4 Feet Ambient to (-)25 °C)
		Dry Heat test	IS 9000 (Part 3/Sec I to V): 1977 (RA 2007)	Qualitative (6 Feet x 4 Feet x 3 Feet Ambient to 300 °C)
		Change of Temperature	IS 9000 (Part 14/Sec I to III): 1988 (RA 2009) IS/IEC 61196-1-206: 2005	Qualitative (6 Feet x 4 Feet x 4 Feet Ambient to (-)25 °C 6 Feet x 4 Feet x 3 Feet Ambient to 300 °C)
		Damp Heat (Steady State) Test	IS 9000 (Part 4): 2008 IEC 60068-2-78: 2012	Qualitative (6 Feet x 4Feet x 4Feet 25 °C to 50 °C 40 % RH to 95 % RH)
		Damp Heat (Cyclic) Test	IS 9000 (Part 5/Sec I & II): 1981 (RA 2007)	Qualitative (6 Feet x 4 Feet x 4 Feet 25 °C to 50 °C 40 % RH to 95 % RH)
		Salt Mist Test	IS 9000 (Part 11): 1983 (RA 2007) IS 9844: 1981 (RA 2010)	Qualitative (760 mm x 760 mm x 760 mm, 35 °C , Spray of 5 % NaCl storage)
		Dust Test	IS 9000 (Part 12): 1981 (RA 2007)	Qualitative (900 mm x 600 mm x 940 mm)

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	Electronic items/ Electrical Items/ Automotive items/ Equipments/ Microcircuits/	Composite Temperature & Humidity Test	IS 9000 (Part 6): 1978 (RA 2007)	Qualitative (6 Feet x 4 Feet x 4 Feet Ambient to (-)25 °C 6 Feet x 4 Feet x 4 Feet 25 °C to 65 °C 40 % RH to 95 % RH)
		Vibration Test	IS 9000 (Part 8): 1981 (RA 2009)	Qualitative (5 Hz to 7 kHz, Force Upto 600 kgf)
		Mechanical Shock Test	IS 9000 (Part 7/Sec I): 1979 (RA 2007)	Qualitative
		Drop & Topple Test	IS 9000 (Part 7/Sec III):1979 (RA 2007)	Qualitative (Drop height 25, 50, 100, 250, 500 mm)
		Free fall Test	IS 9000 (Part 7/Sec 4): 1979 (RA 2007)	Qualitative (Drop height 25, 50,100, 250, 500, 1000 mm)
		Free fall Repeated	IS 9000 (Part 7/Sec 5): 1979 (RA 2007)	Qualitative (Number of fall : 50, 100 200, 500, 1000)
		Low Air Pressure Test/ Altitude Test	IS 9000 (Part 13): 1981 (RA 2007)	Qualitative (2.66 kPa to 99.99 kPa)
		Robustness of Terminations Test	IS 9000 (Part 19/Sec I to V): 1986 (RA 2007)	Qualitative
		Resistance to Cleaning Solvents and permanence of Markings	IS 9000 (Part 20): 1979 (RA 2007)	Qualitative

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	Electronic items/ Electrical Items/ Automotive items/ Equipments/ Microcircuits/	Fine Mist Test	IS 9000 (Part 22): 1983 (RA 2007)	Qualitative
		Degrees of Protection Provided by Enclosures (IP Code)	IS/IEC 60529: 1989 (Amd. 1: 1999, Amd. 2: 2013)	Qualitative

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